Notice of References Cited Application/Control No. 09/739,817 Examiner JOHN J LEE Applicant(s)/Patent Under Reexamination MIYANO ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,305,353	04-1994	Weerackody, Vijitha	375/347
	В	US-6,300,900	10-2001	Bleret et al.	342/361
	С	US-6,697,641	02-2004	Shapira, Joseph	455/562.1
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	V						
	w						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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